

Development of Superconducting Tunnel Junction(STJ) Photon Detector on SOI Preamplifier Board to Search for Radiative Decays of Cosmic Neutrino Background

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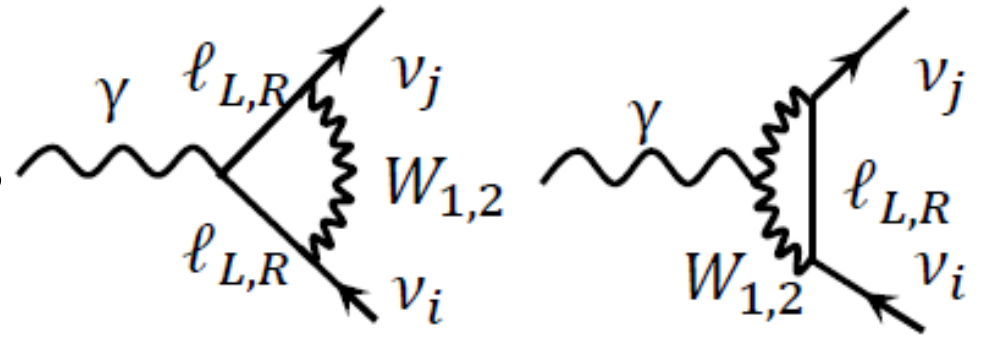
Outline

- **Motivation(Search for Neutrino Radiative Decay)**
- **Introduction of Superconducting Tunnel Junction(STJ)**
- **STJ on Silicon-on-Insulator Preamplifier-board(SOI-STJ)**
- **Current Status on development of SOI-STJ**
- **Future Plan**
- **Summary**

Motivation

Neutrino Mass Measurement

- We know that neutrinos have small mass but neutrino mass itself have not been measured.
- Aiming at measuring neutrino mass itself with Neutrino Radiative Decay.



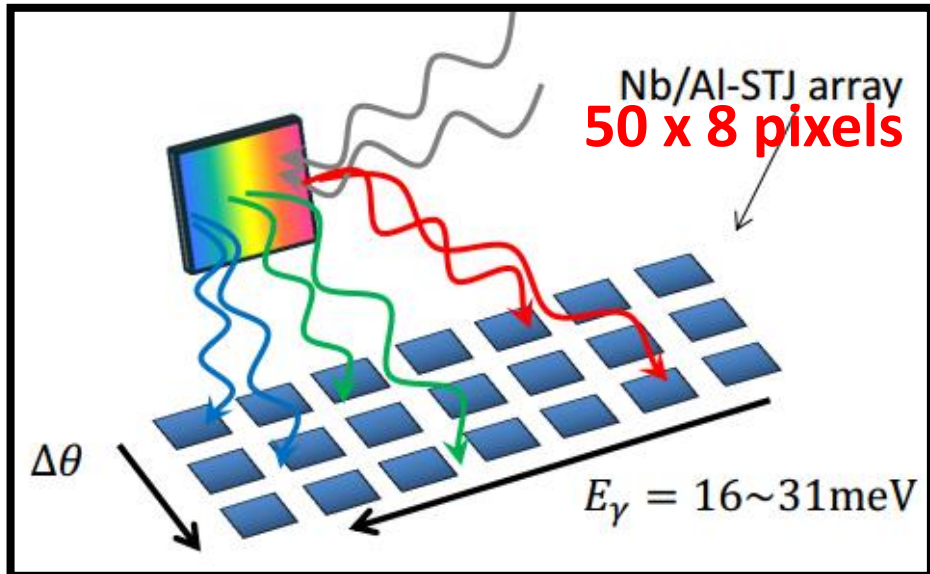
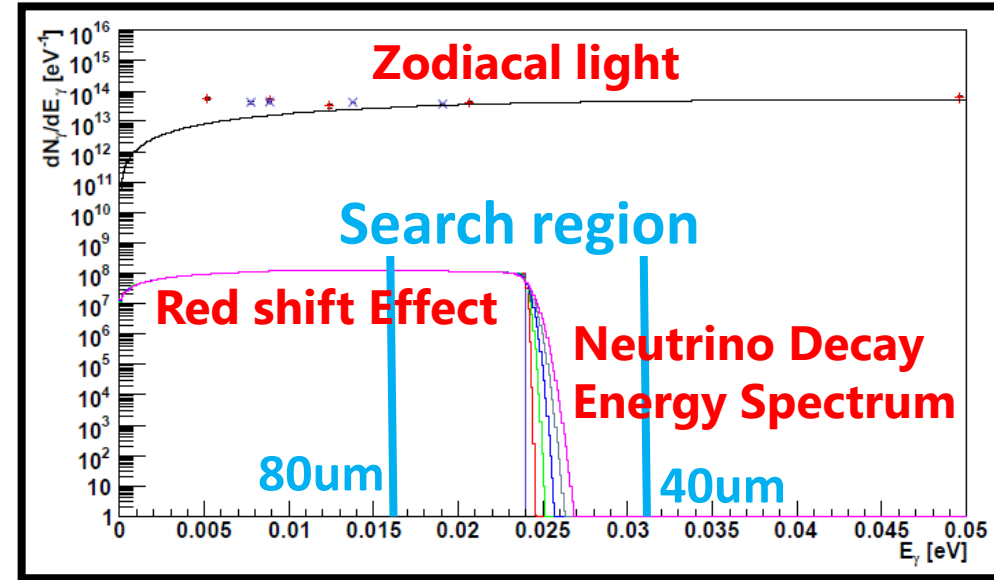
$$E_\gamma = \frac{m_3^2 - m_2^2}{2m_3}$$

Lifetime of Neutrino ($\nu_3 \rightarrow \nu_{1,2} + \gamma$)

- 10^{43} years in SM expectation, $\tau \gtrsim O(10^{17})$ years in left-right symmetric model ($SU(2)_L \otimes SU(2)_R \otimes U(1)_{B-L}$)
- Present limit is 3×10^{12} years (AKARI).
- We will use **Cosmic Neutrino Background** as neutrino source for Neutrino Decay.

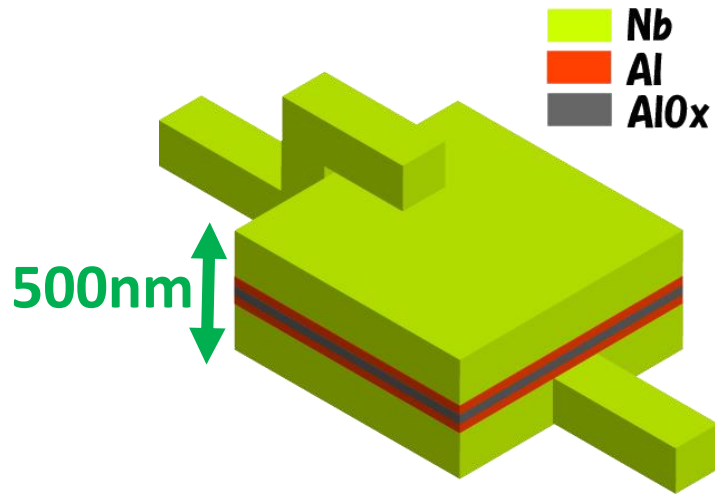
Requirements for the Detector

- Expected energy of photon in neutrino radiative decay is $E_\gamma = 25 \text{ meV}$ ($m_3 = 50 \text{ meV}$ is assumed).
- In this region, biggest background is zodiacal light.
- To detect the neutrino radiative decay significantly in CIB, We need the photon detector which has **2% energy resolution for 25meV(50um)**.



- Nb/Al-STJ photon detector (50 x 8 pixels) with grating is a candidate for our experiment.
- Aiming at improving the current experimental lower limit of the neutrino lifetime by 2 order in rocket experiment: $\tau(\nu_3) > O(10^{14} \text{ years})$

STJ Photon Detector



Number of Quasi-particles in Nb/Al-STJ

$$N_q = G_{Al} E_0 / 1.7\Delta$$

G_{Al} : Trapping Gain In Al (~10)

E_0 : Photon Energy

Δ : E-Gap in superconductor

For 25meV single photon

$$N_q = 10 \frac{25 \text{ meV}}{1.7 * 1.550 \text{ meV}} = 95 e$$

What's STJ (Superconducting Tunnel Junction) ??

STJ is a Josephson Junction composed of

Superconductor / Insulator / Superconductor.

Principle of Operation

1. Photon absorbed in superconducting layers of STJ during applying magnetic field.
2. Excites cooper pair into quasi-particles according to absorbed energy.
3. Observe tunneling current due to quasi-particles through the insulator.

	Si	Nb	Al
Tc[K]		9.23	1.20
Δ [meV]	1100	1.550	0.172

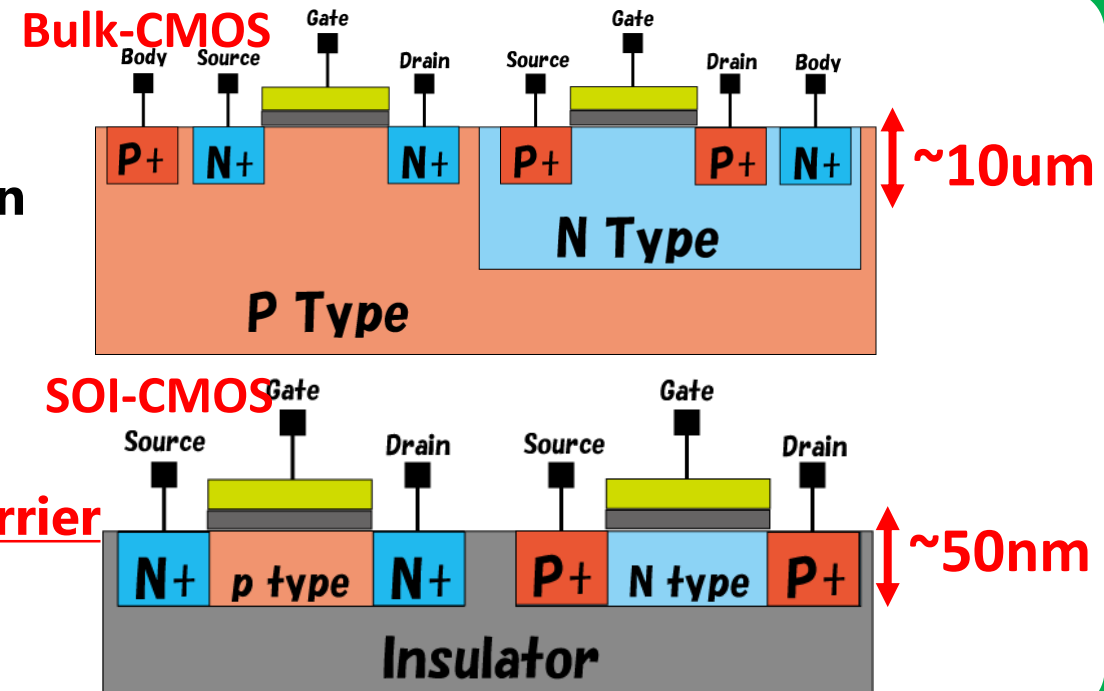
Development of cold preamplifier

- Current Status of Development for Nb/Al-STJ (if you want to know detail, please see Yuji TAKEUCHI's slides- II .c Neutrino session 12:00-).
 - We haven't succeeded in detecting a far-infrared single photon yet due to **readout noise (thermal noise and cable noise)**.
 - Need to adopt the preamplifier operated at ultra-low-temperature.
 - FD-SOI device was proved to operate at 4K by a JAXA/KEK group (AIPC 1185,286-289(2009)).

Silicon on Insulator (SOI)

- Processing LSI on SiO_2 Insulator.
- Very Small Parasitic Capacitance due to Separation between MOSFETs with insulator (Not Depletion).
 - Low-Power to be Operated (400 μW)
 - High Speed (1 MHz)
 - Good at Large Scale Integration
 - Suppression of charge-up by high mobility carrier due to thin depletion layer ($\sim 50\text{nm}$).

➡ Apply this to readout of STJ signal !



Requirement for the amplifier of STJ readout.

□ Operation at ultra-low temperature

- Requirement for leakage current of Nb/Al-STJ is below 100pA.

But practically, leakage current is caused by...

- **Pinhole(constant) across the insulator**
 - We can expect to reduce it by using smaller one.
- **Thermal excitation** ($\propto \sqrt{T} e^{-\frac{\Delta}{k_b T}}$)
 - -We need to make cooler to 800mK.

➡ **1. Operating below 800mK**

3He sorption is better

□ Low power consumption

- Typical cooling power of our refrigerator is 400uW.

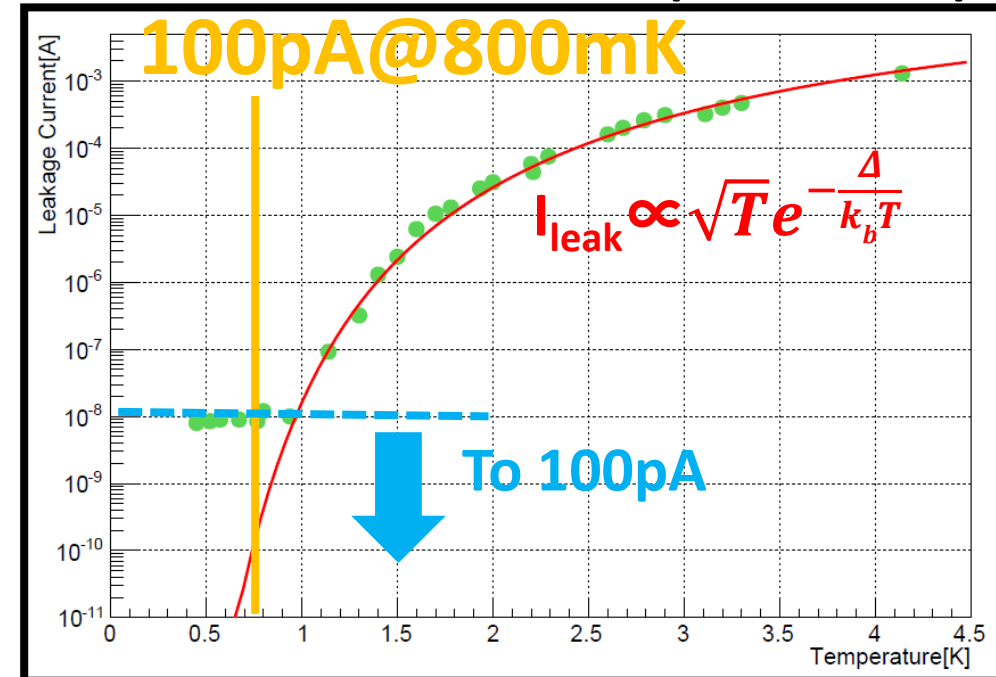
➡ **2. Power consumption in the amplifier is as low as possible.**

□ Speed

- We think that integration region of charge is from 1uS to 4uS.

➡ **3. amplifying up to 1MHz is sufficiently good to apply it.**

Temperature Dependence of Dark Current with Nb/Al-STJ(10000um²)



SOI-STJ

What's SOI-STJ ?

Processing Nb/Al-STJ on SOI preamplifier board directly.

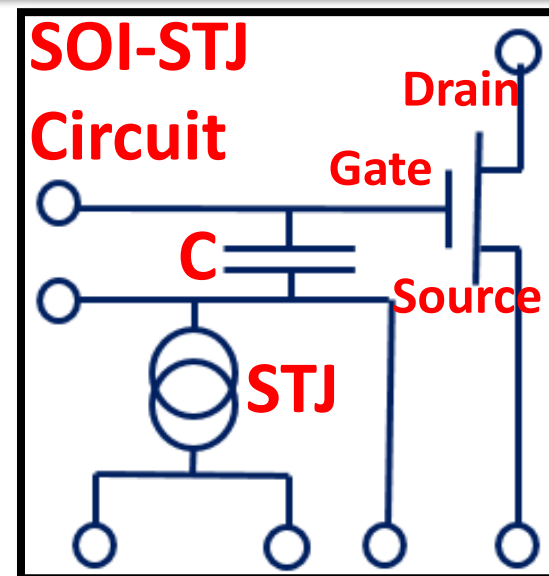
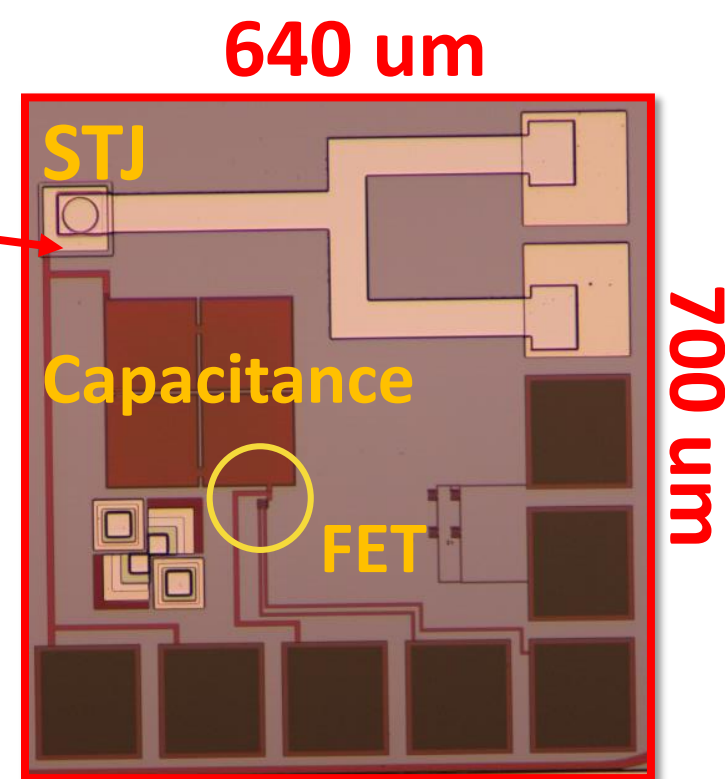
- **Expected good signal-to-noise ratio.**
- **Potential for expansion of multi-pixel device**

The first prototype of SOI-STJ

We tested the Nb/Al-STJ on SOI wafer which only include MOSFET to answer the following questions:

- SOI-FET has no damage by processing STJ ?
- Quality of Nb/Al-STJ can be good on SOI wafer ?

Via(W) for
Electrical Contact

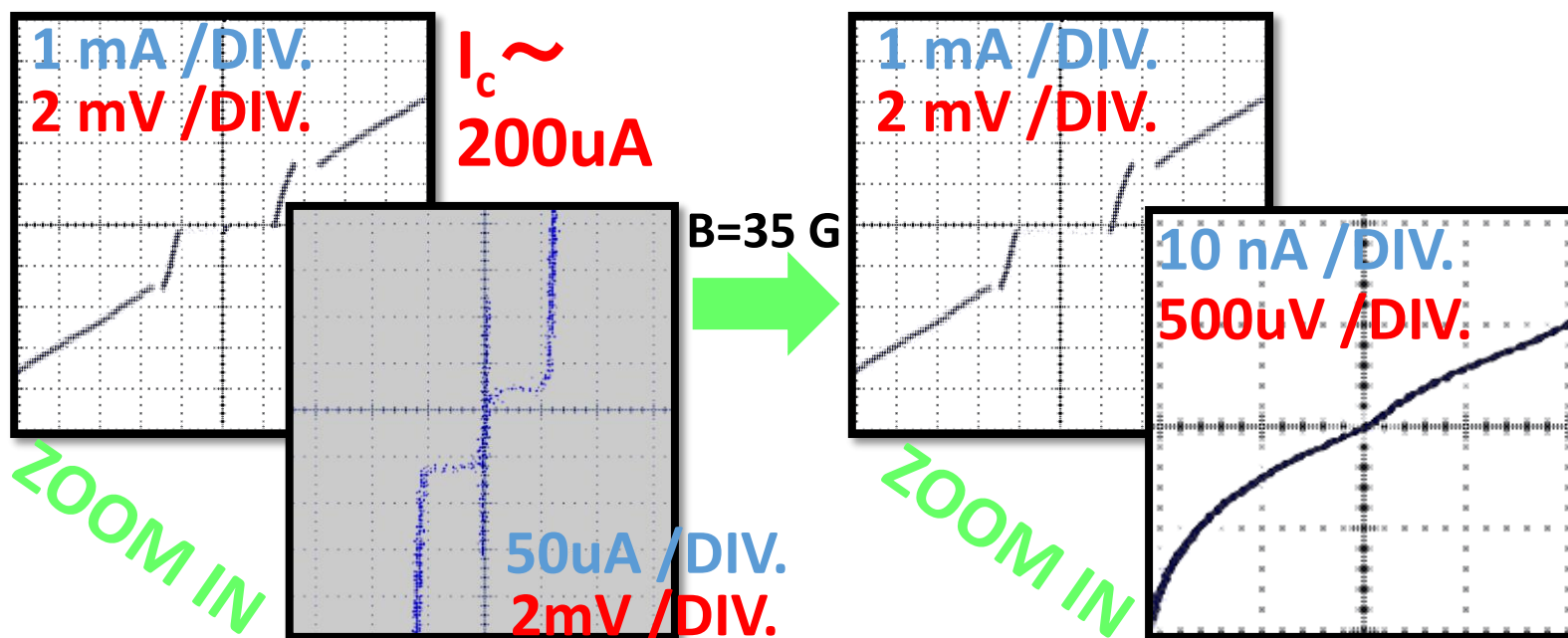
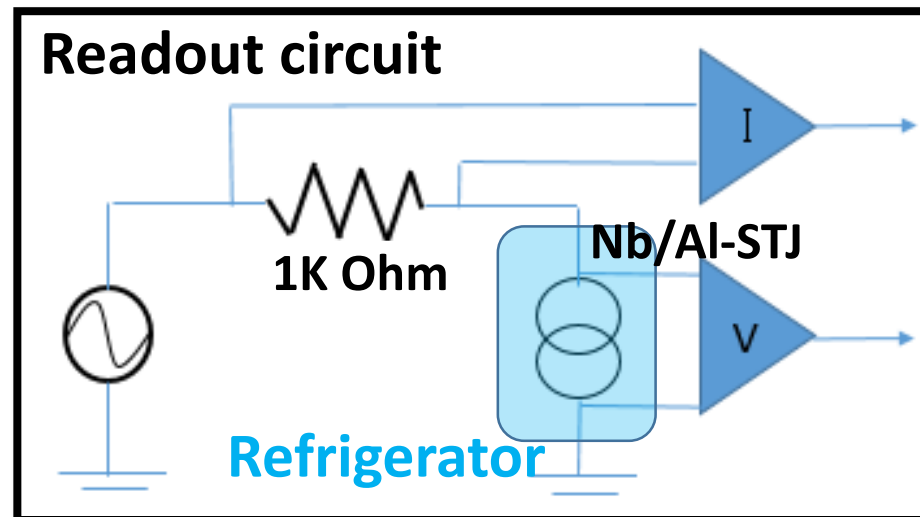


Nb/Al-STJ can be processed on SOI wafer perfectly ?

We have measured I-V curve of Nb/Al-STJ (50um x 50um junction) processed on SOI wafer

At **700mK** with dilution refrigerator.

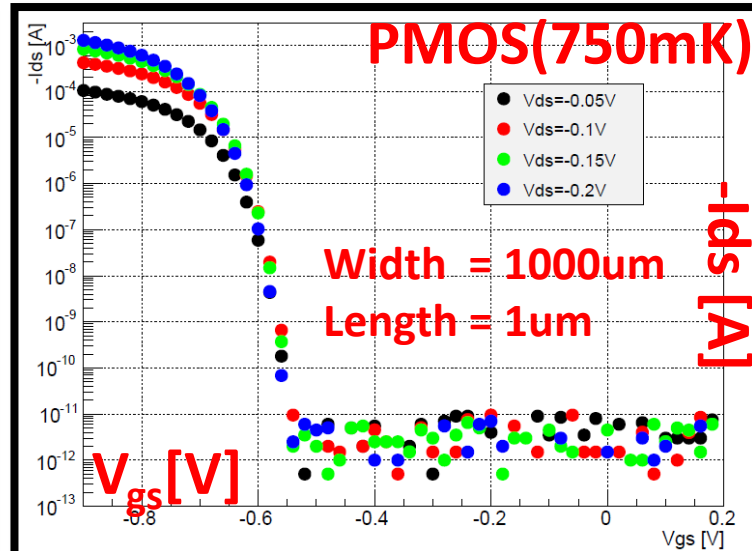
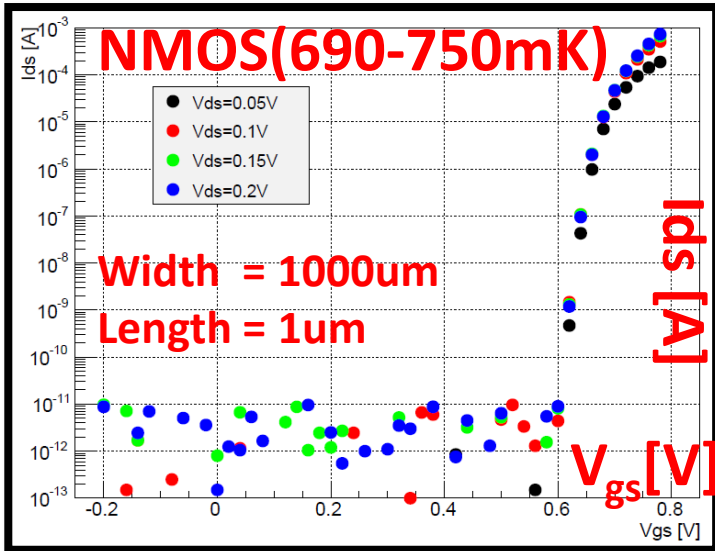
□ We have seen the distinctive I-V curve of Josephson Junction !



□ Leak current @ 0.5mV is **6nA**. It's almost same as our best record of normal Nb/Al-STJ(100um x 100um) 10nA.

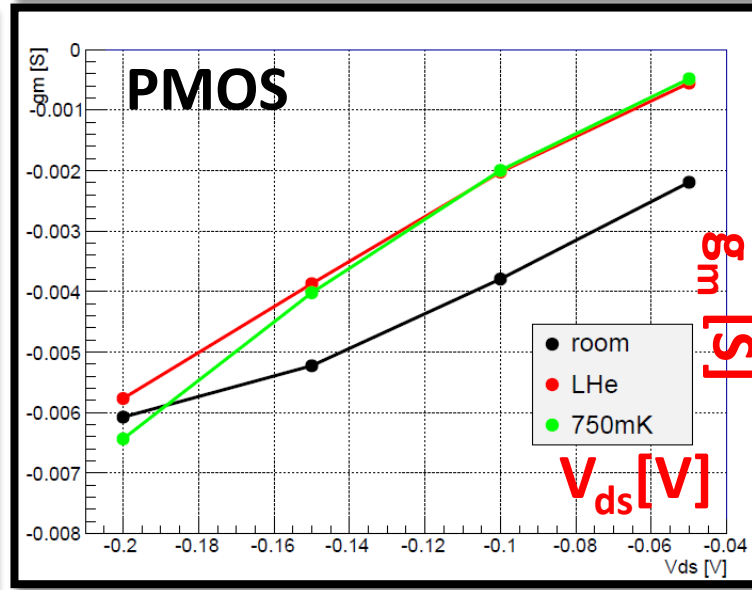
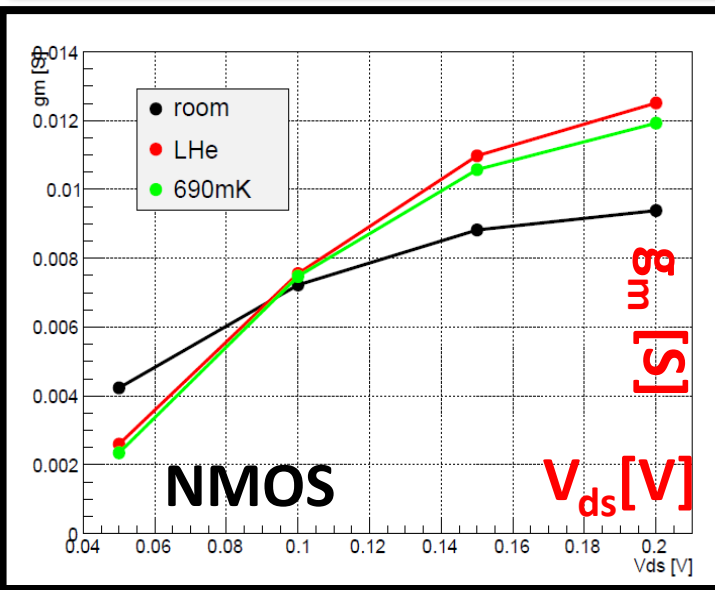
□ Quality Factor ($R_{\text{dynamic}}/R_{\text{normal}}$)
On Si wafer : 5×10^5
On SOI wafer : 3×10^5

1. SOIFET can be operated below 800mK ?



I-V curve of SOIFETs after processing Nb/Al-STJ.

- Both of NMOS and PMOS could be operated below 800mK.
- Trans-conductance " g_m " was not varied drastically for each temperature at operation voltage(0.2V).



**We can use these as
Preamplifier for STJ signal
at ultra-low temperature.**

Excellent performance !!

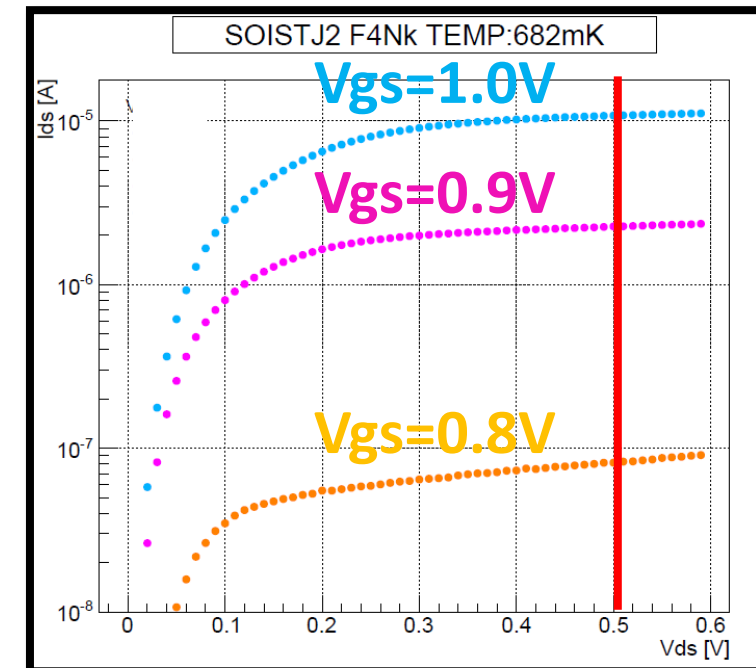
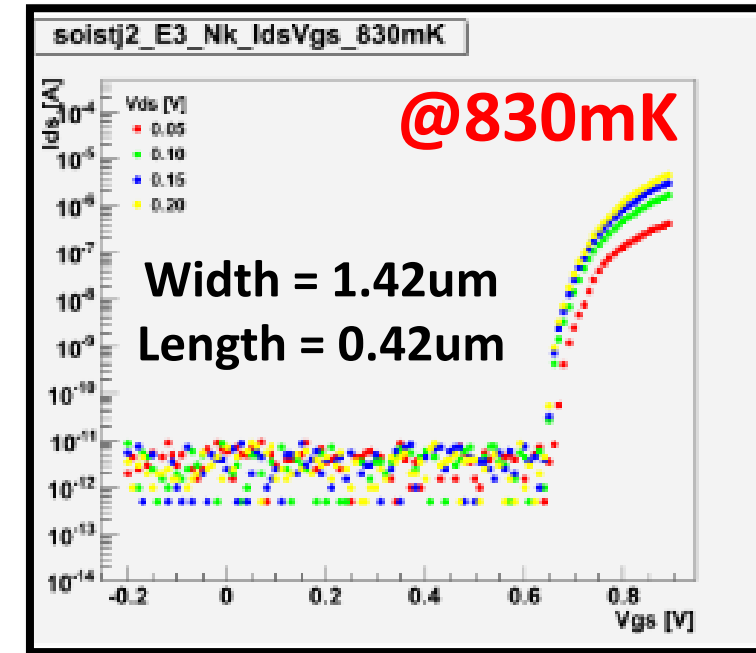
2. Power Consumption of SOIFET

- Bias voltage of SOI-FET in saturation region (red line at right figure) : **0.5 V**
- Current (I_{ds}) of FET in saturation region at $V_{gs} = 0.8V$: **0.09 μA**

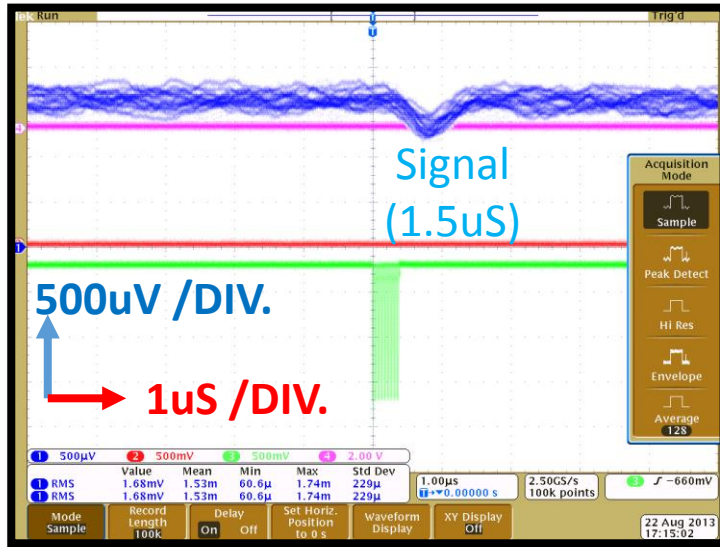
Power consumption = **0.5 V** \times **0.09 μA**

$$= \underline{\underline{45 \text{ nW/FET (W/L=3.4)}}}$$

- We need to calculate the thermal model in rocket experiment firstly.
- We investigate the possibility of using it around the threshold voltage (lower power and higher gain are expected, but lower speed).



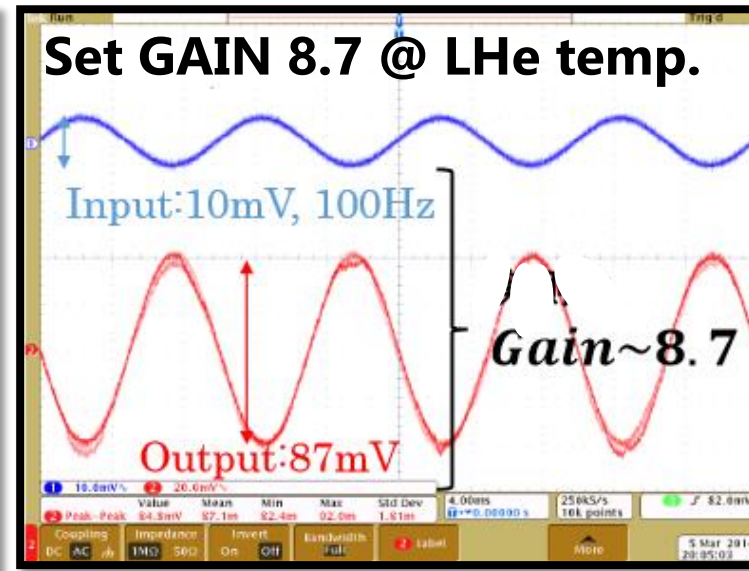
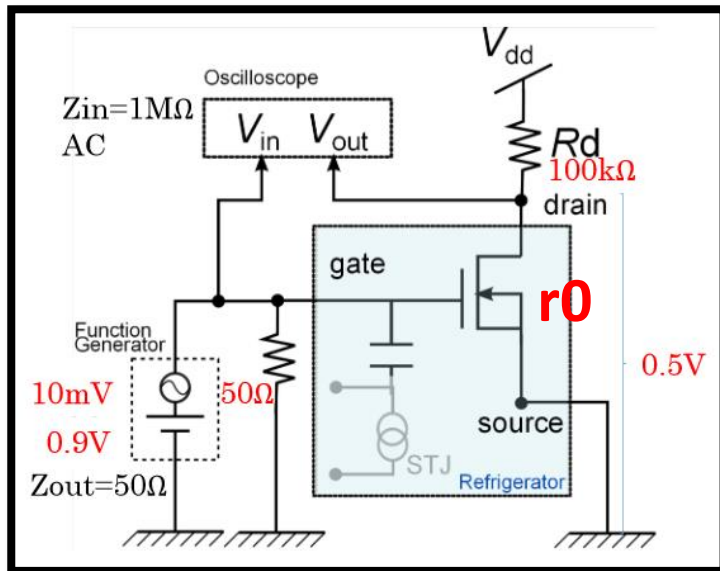
3. Frequency dependence of SOIFET



- We observed the signal of Nb/Al-STJ processed on SOI board to 465nm laser pulse.
- The width of the signal of Nb/Al-STJ is about **1 uS**.

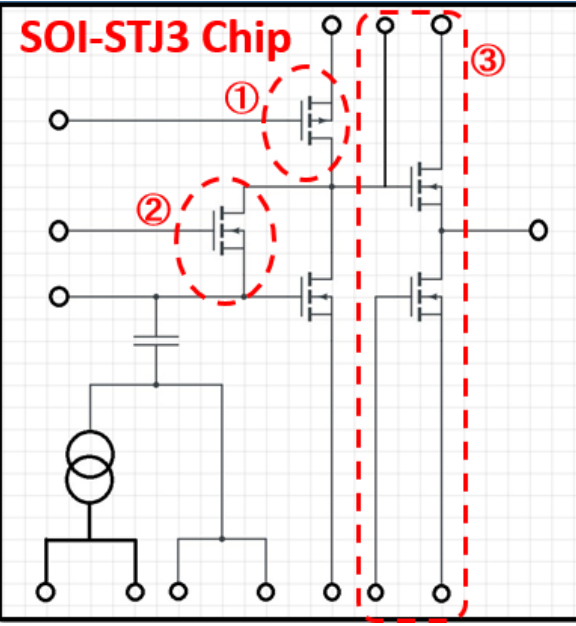


Our requirement for the amplifier is operation above 1 MHz in order to best S/N.



- We Checked the behavior of SOI-FET as the preamplifier.
- But we can not measure the gain at high frequency due to too large output impedance.

Future Plans

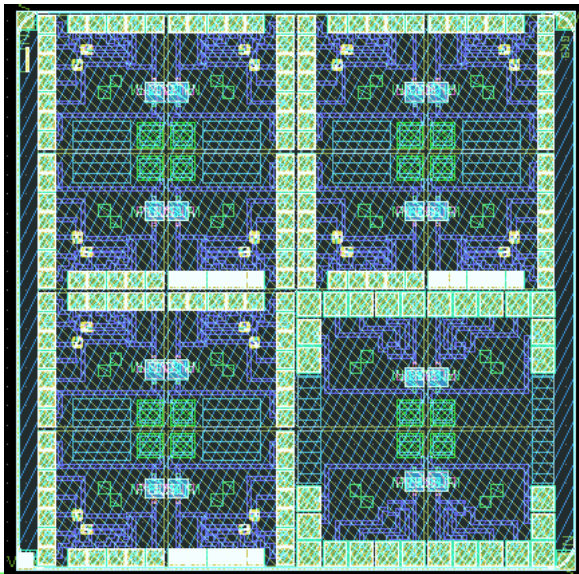


- We are updating the SOI-STJ schematic for amplification of the Nb/Al-STJ signal.

Designed the ratio (W/L) so that the operation power is below 120uW.

1. Replace the resistance to SOI-FET that we use as current source.
2. Employ the Feedback between drain and gate to apply stable bias voltage
3. Add the follower to reduce the Output Impedance.

In current status, We will measure the response to laser pulse with renewed SOI-STJ soon.

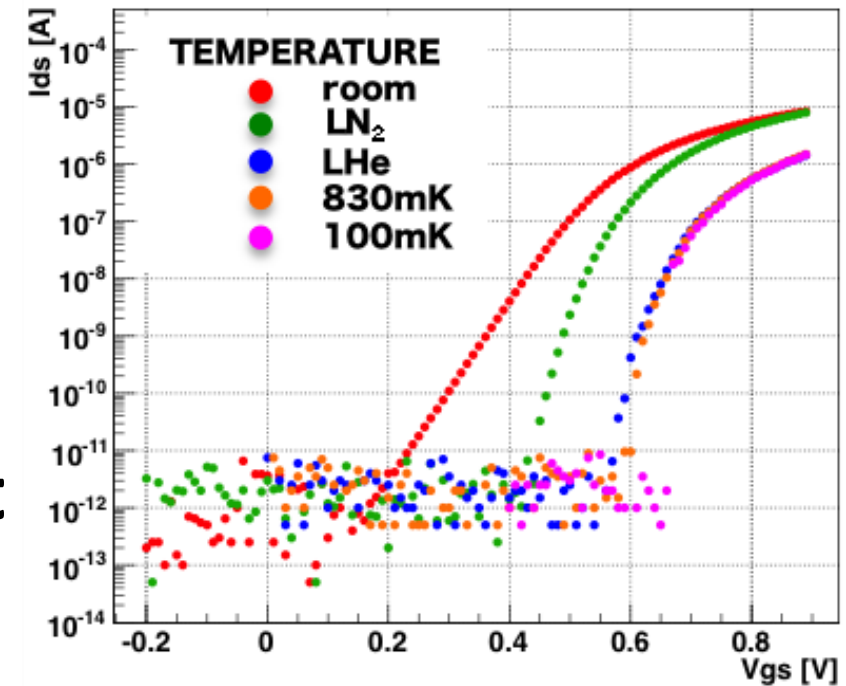


Summary

- SOI-STJ photon detector is under development for detecting far-infrared single photon for neutrino mass measurement.
- We processed Nb/Al-STJ on SOI-FET board and confirmed the following performances.

- **SOIFET has no damage by processing Nb/Al-STJ.**
- **Nb/Al-STJ is also operated normally.**
- **SOIFET can be operated below 800mK.**

***For your information, we also confirmed that SOIFET can be operated at 100mK.**



Back Up Slides



The I-V curve of Josephson junction

How can we check the performance of STJ??

□ Josephson Junction has distinctive I-V curve.

□ Blue region

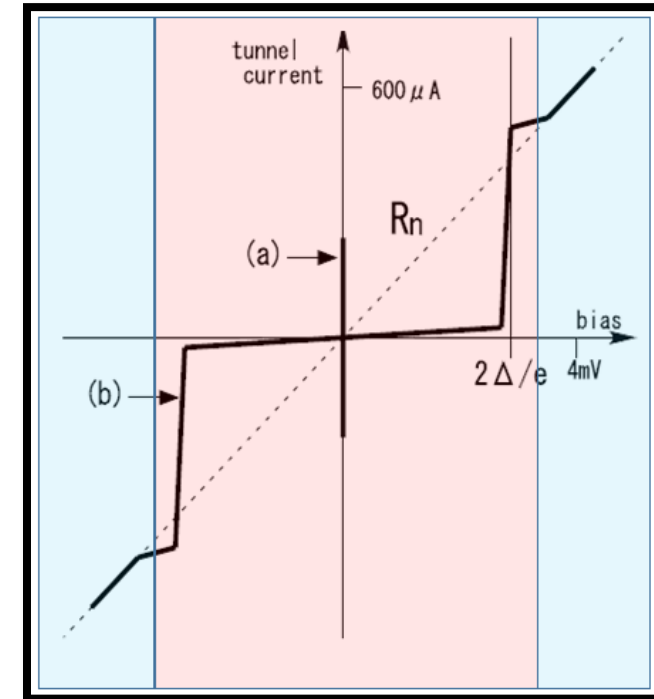
- Cooper pairs can go through directly the other electrode due to larger bias than gap energy.

□ Red region

- The cooper pair tunneling Current is seen at $V = 0V$.
- This is suppressed during applying Magnetic fields.

□ The leakage current at operation voltage(0.5mV) deteriorate of energy resolution.

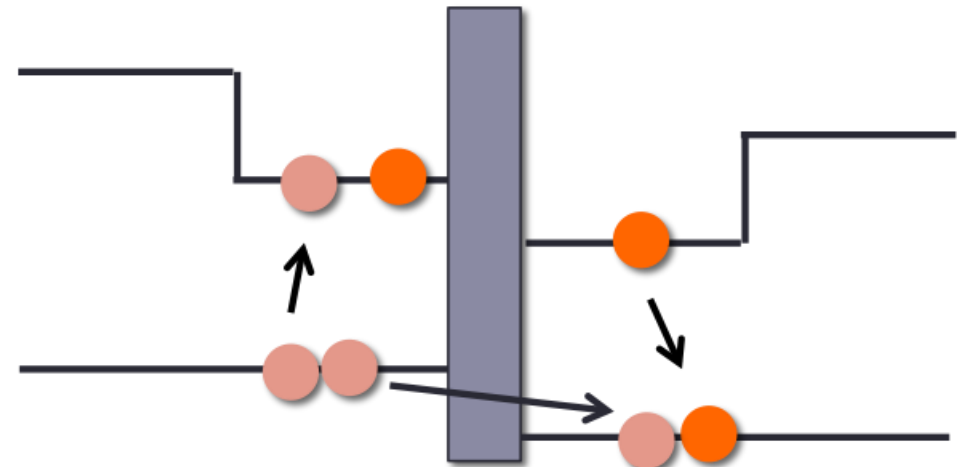
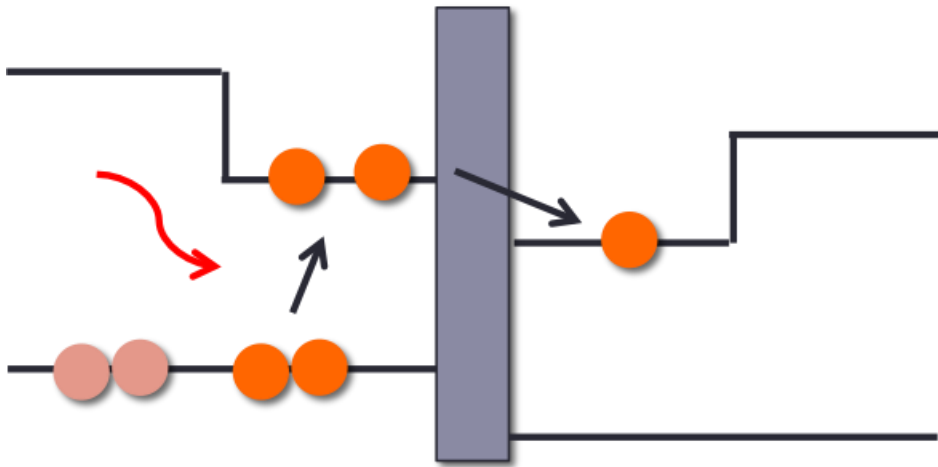
- To discriminate signal from leakage current fluctuation, **the leak current of the Nb/Al-STJ should be below 100pA(Our best sample has 10nA).**



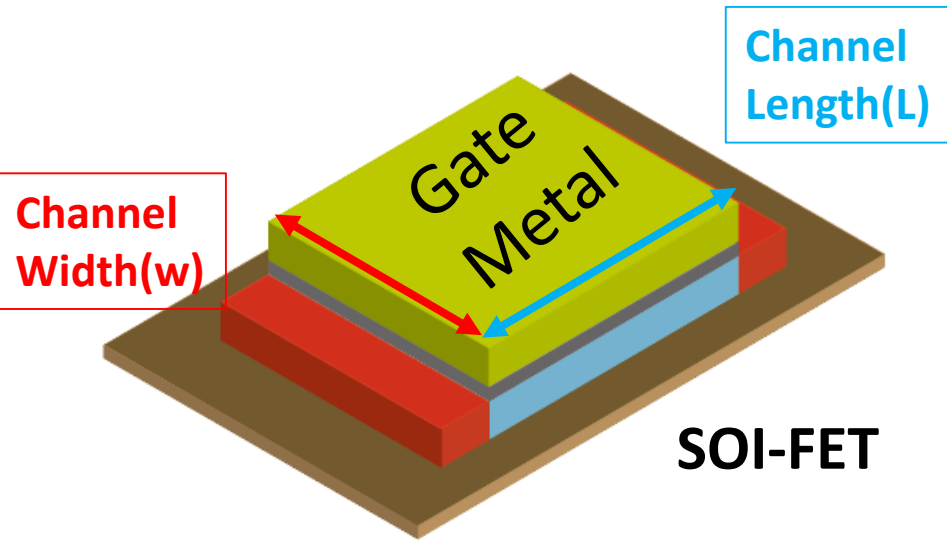
Trapping Gain

STJ Back tunneling

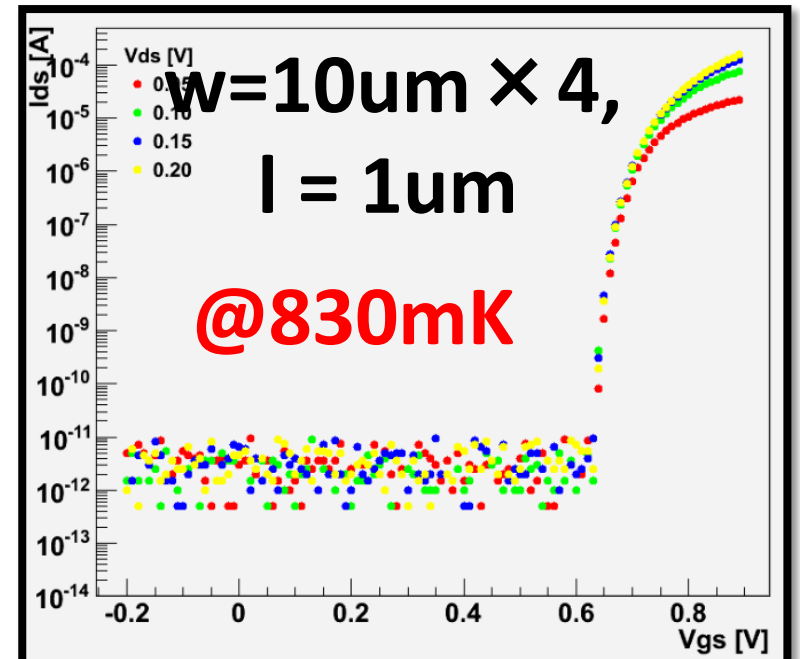
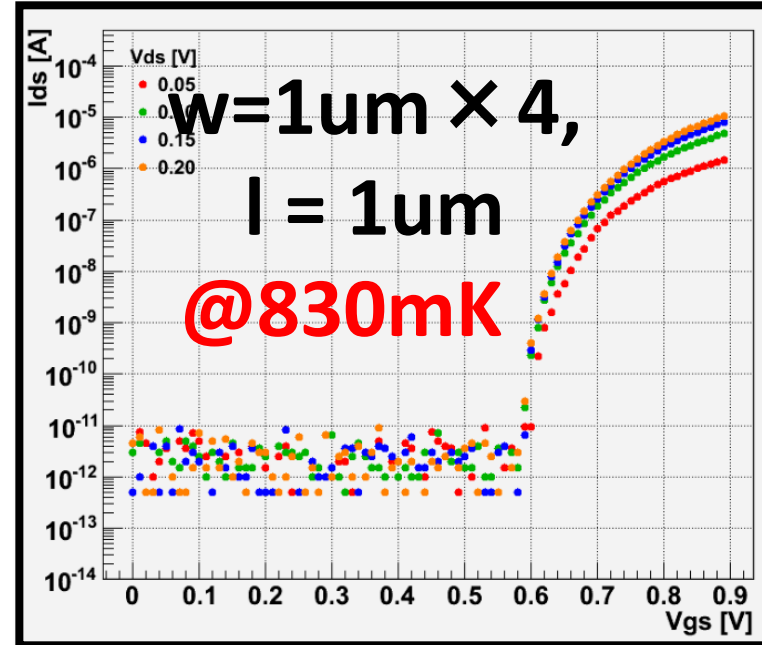
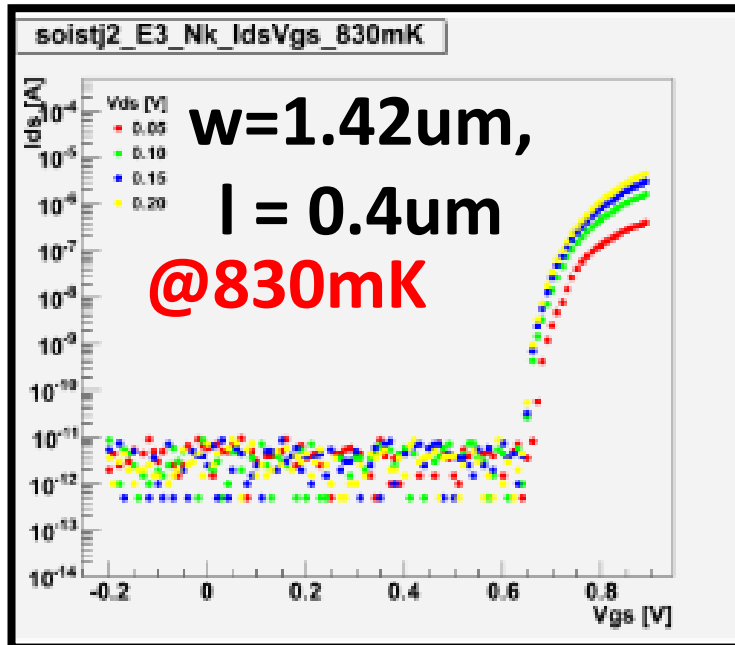
- When quasi-particle that is created around insulator go through the insulator layer, then quasi-particle break cooper pair in opposite layer and make cooper pair with one of quasi-particles.



I-V curve of SOIFET @ ultra-low temperature



We can see the I-V curve for each W/L value.



Requirement for leakage current of Nb/Al-STJ

When far-infrared single photon incident to the Nb/Al-STJ, Number of created quasi-particle in STJ is around **100e** (assuming $G_{al} = 10$). We want to separate between the signal and pedestal (3 sigma). so requirement for fluctuation of the leakage current of STJ is follow.

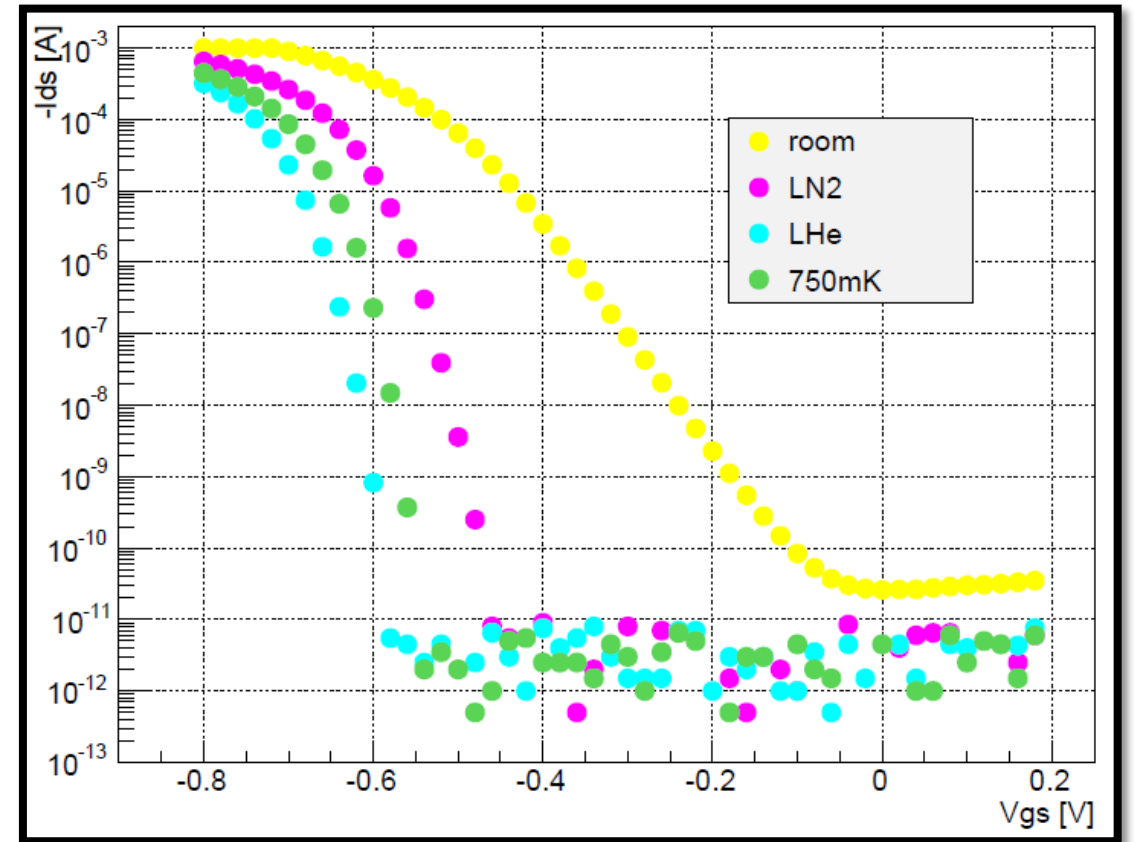
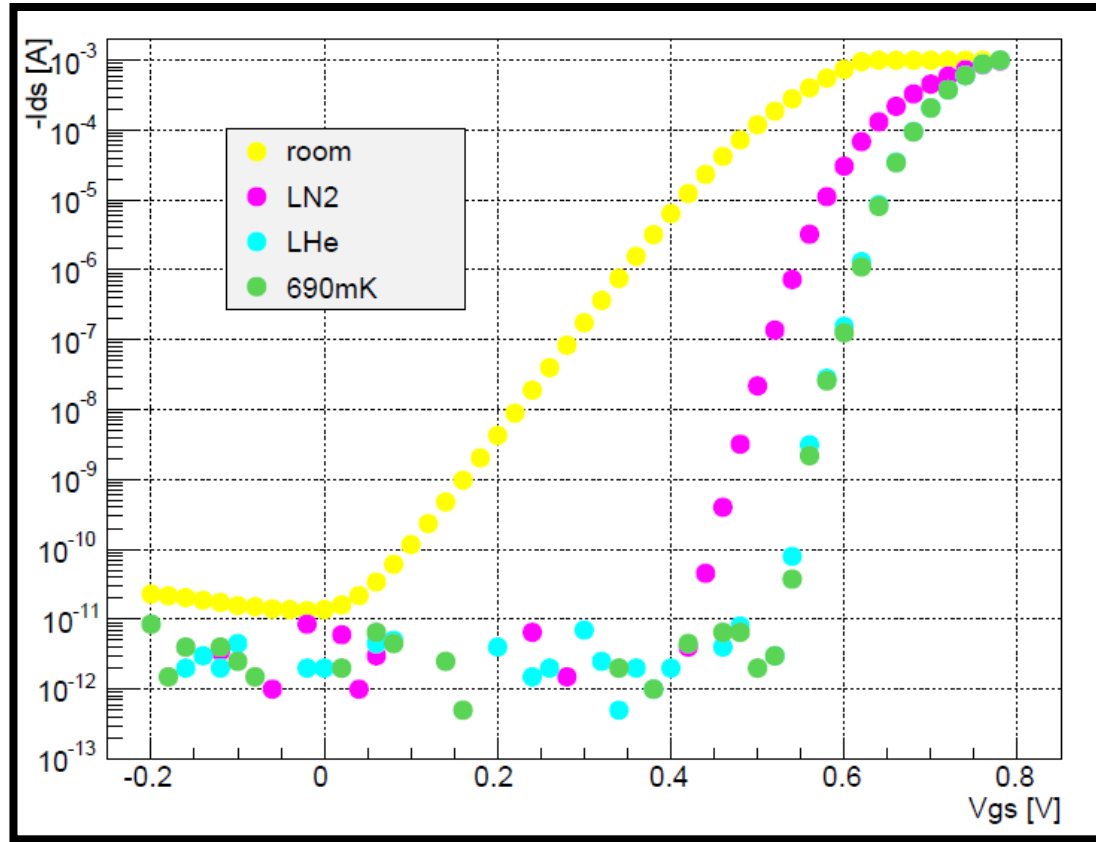
$$\delta N_{qleak} = 33 e$$

If we assume that integration width is 1.5 uS, our requirement for the leakage current is...

$$N_{qleak} = 1089 e$$

$$I_{leak} = \frac{1089 \times 1.6 \times 10^{-19}}{1.5 \times 10^{-6}} = 108 [pA]$$

Temperature Dependence of I-V curve



Threshold voltage is changed. But the other properties are almost unchanged.

Energy resolution of Nb/Al-STJ

Energy Resolution of STJ

$$\delta E_{\text{FWHM}} = 2.35 \sqrt{(1.7\Delta)FE}$$

F : Fano Factor

Δ : Gap energy

E : Photon energy

For 25meV single photon

$$\frac{\delta E_{\text{FWHM}}}{E} = 2.35 \sqrt{\frac{(1.7\Delta)FE}{E}} = 22\%$$